

United States Patent and Trademark Office

UNITED STATES DEPARTMENT OF COMMERCE United States Patent and Trademark Office Address: COMMISSIONER FOR PATENTS P.O. Box 1450 Alexandria, Virginia 22313-1450 www.uspto.gov

APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/600,850	06/20/2003	Ayumu Oda	59408 (49321)	6007
21874	7590 12/09/2005		EXAMINER	
	& ANGELL, LLP		PHAM, F	IAI CHI
P.O. BOX 55874 BOSTON, MA 02205			ART UNIT	PAPER NUMBER
·			2861	

DATE MAILED: 12/09/2005

Please find below and/or attached an Office communication concerning this application or proceeding.

	Application No.	Applicant(s)			
	10/600,850	ODA ET AL.			
Office Action Summary	Examiner	Art Unit			
	Hai C. Pham	2861			
The MAILING DATE of this communication app					
Period for Reply					
A SHORTENED STATUTORY PERIOD FOR REPLY WHICHEVER IS LONGER, FROM THE MAILING DA - Extensions of time may be available under the provisions of 37 CFR 1.13 after SIX (6) MONTHS from the mailing date of this communication. If NO period for reply is specified above, the maximum statutory period w - Failure to reply within the set or extended period for reply will, by statute, Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	ATE OF THIS COMMUNICATION 36(a). In no event, however, may a reply be tim vill apply and will expire SIX (6) MONTHS from cause the application to become ABANDONEI	l. the mailing date of this communication. (35 U.S.C. § 133).			
Status					
Responsive to communication(s) filed on <u>20 Second</u> This action is FINAL . 2b)⊠ This Since this application is in condition for allowar closed in accordance with the practice under Expression in the Expression in the practice under Expression in t	action is non-final. nce except for formal matters, pro				
Disposition of Claims					
 4) Claim(s) 1,3-13 and 15-22 is/are pending in the 4a) Of the above claim(s) is/are withdraw 5) Claim(s) is/are allowed. 6) Claim(s) 1,3-13 and 15-22 is/are rejected. 7) Claim(s) is/are objected to. 8) Claim(s) are subject to restriction and/or 	vn from consideration.				
Application Papers	·				
9) The specification is objected to by the Examiner 10) The drawing(s) filed on is/are: a) access applicant may not request that any objection to the confidence of the	epted or b) objected to by the Eddrawing(s) be held in abeyance. See ion is required if the drawing(s) is obj	e 37 CFR 1.85(a). ected to. See 37 CFR 1.121(d).			
Priority under 35 U.S.C. § 119					
 12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a) All b) Some * c) None of: 1. Certified copies of the priority documents have been received. 2. Certified copies of the priority documents have been received in Application No 3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)). * See the attached detailed Office action for a list of the certified copies not received. 					
Attachment(s) 1) Notice of References Cited (PTO-892) 2) Notice of Draftsperson's Patent Drawing Review (PTO-948) 3) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08) Paper No(s)/Mail Date	4) Interview Summary Paper No(s)/Mail Da 5) Notice of Informal P 6) Other:				

Application/Control Number: 10/600,850

Art Unit: 2861

DETAILED ACTION

Page 2

Claim Objections

1. Claims 1, 10 and 21 are objected to because of the following informalities:

Claim 1:

 Line 3, "an optical writing unit" should read --said optical writing unit-- since it has been recited in the preamble.

Claim 10:

 Line 7, "an optical writing unit" should read --said optical writing unit-- since it has been recited in the preamble.

Claim 21:

Line 10, "an optical writing unit" should read --said optical writing unit-- since it
has been recited earlier within the claim.

Appropriate correction is required.

Claim Rejections - 35 USC § 103

- 2. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

Art Unit: 2861

3. Claims 1, 4, 7-13, 16, 19-22 are rejected under 35 U.S.C. 103(a) as being unpatentable over lannazzi (U.S. 6,842,188) in view of Deguchi et al. (U.S. 6,061,526).

lannazzi discloses a method and apparatus for adjusting the focus of a multichannel printhead (500), the method comprising forming a test pattern including a multiple pattern elements disposed along an image forming area in a main scanning direction (density patches 82) (Fig. 4), said multiple pattern element being of varying density levels corresponding to different amounts of adjustment (the test patch being formed by randomly varying the focus position of the printhead so as to have varying density levels corresponding to different focus positions of the printhead), and adjusting the position of the printhead relative to the surface of the image-carrying member (drum 300) by the amount of adjustment indicated by the measured density levels of the multiple pattern elements (col. 3, lines 13-25 and col. 7, line 26 to col. 8, line 40).

However, lannazzi teaches the density patches having small gaps and thus fails to teach the test pattern being an uninterrupted pattern, the test pattern being binary pattern elements (claims 4, 16), both ends of the optical writing unit are affixed to an adjustment mechanism (claim 9), a memory for storing the test pattern (claims 10, 12, 21),

Deguchi et al. discloses an image recoding apparatus including a focus position control device for adjusting the focus position of the printhead based on the density test pattern that includes uninterrupted multiple test patterns arranged in the main scanning direction (Fig. 19). Deguchi et al. further teaches the test pattern having 256 density levels provided by an 8-bit image data, and the ends of the exposure head (220) being

Art Unit: 2861

affixed to an adjustment mechanism, i.e., spacer (202), screw mechanism (203) or wedge (204) (Figs. 15a-15c), a memory for storing the test pattern (LUT data for LUT gradation conversion processing).

It would have been obvious at the time the invention was made to a person having ordinary skill in the art to modify the test pattern in the device of lannazzi to include uninterrupted test patterns as well as providing appropriate adjusting mechanism as taught by Deguchi et al. The motivation for doing so would have been to provide an accurate focus adjustment mechanism according to the linearly varying density levels.

lannazzi further teaches:

- Adjustment quantity information showing the amount of adjustment corresponding to the density levels being indicated by the test pattern (e.g., the focus position adjustment being based on the fine focus proof chart as shown in Fig. 5);
- installing the optical writing unit at an offset position closer to or farther away
 from the image-carrying member (e.g., randomly varying the focus position of the
 printhead relative to the drum so as to have varying density levels corresponding
 to different focus positions of the printhead);
- a retainer for holding the writing unit (translation stage member 220), an actuator (focus motor 51) for providing the moving mechanism with motive power for varying the position of the optical writing unit;

Application/Control Number: 10/600,850 Page 5

Art Unit: 2861

 reading an image of the test pattern formed on the printing medium (e.g., using a densitometer).

4. Claims 3, 5-6, 15 and 17-18 are rejected under 35 U.S.C. 103(a) as being unpatentable over lannazzi in view of Deguchi et al., as applied to claims 1 and 10 above, and further in view of Patten et al. (Pub. No. U.S. 2002/0196473).

lannazzi in view of Deguchi et al. further teaches the density levels of the test pattern corresponding to light emitting time/power of the individual light emitting elements (Deguchi et al., Fig. 17), but fails to teach the density levels being determined by the diameter of individual dots.

Pattern et al. discloses a focus adjustment mechanism by printing a continuous test patterns along the main scanning direction (Fig. 5A), the test patterns having varying density levels, which are defined by the size or diameter of the spot on the imaging surface, or by varying the exposure level.

It would have been obvious at the time the invention was made to a person having ordinary skill in the art to form the test pattern based on the individual dot diameter as taught by Patten et al. since Patten et al. teaches this to be well known art to either vary the size of the dot diameter or the exposure power to provide a test pattern of varying density, the implement of which would only require routine skill in the art.

Application/Control Number: 10/600,850

Art Unit: 2861

Response to Arguments

Page 6

5. Applicant's arguments with respect to claims 1, 3-13 and 15-22 have been considered but are moot in view of the new grounds of rejection as presented in this Office action.

Contact Information

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Hai C. Pham whose telephone number is (571) 272-2260. The examiner can normally be reached on M-F 8:30AM - 5:30PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, David L. Talbott can be reached on (571) 272-1934. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

HAI PHAM
PRIMARY EXAMINER

Har DiPham

December 7, 2005